

Notice of References Cited

Application/Control No.

10/597,976

Applicant(s)/Patent Under

Reexamination

REDERT ET AL.

Examiner

Carlos Perromat

Art Unit

2628

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
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H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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NON-PATENT DOCUMENTS

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V	Z. Wu, L. Li; A Line-Integration Based Method for Depth Recovery from Surface Normals; IEEE, November 1988
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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